



SILICON HETEROJUNCTION METALLIZATION AND MODULES APPROACHES

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MEYER BURGER



Si Heterojunction Cells: Fabrication Sequence

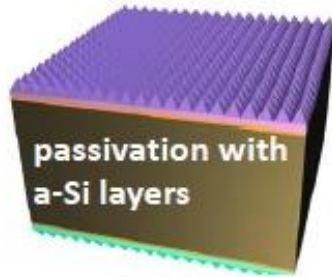
Chemical
baths
c-Si surface
preparation

PECVD I
Intrinsic
film
deposition
 $a\text{-Si:H}(i)$

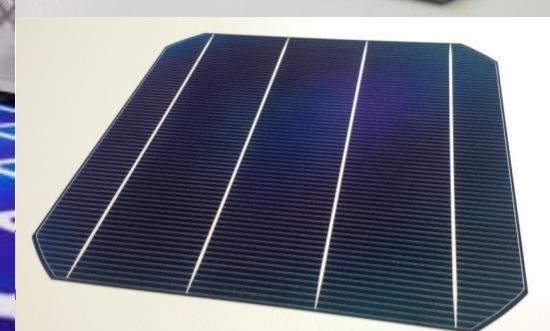
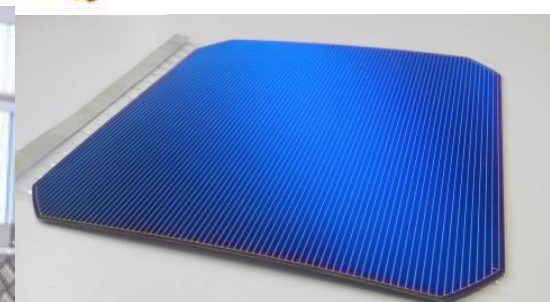
PECVD II
Doped film
deposition
 $a\text{-Si:H}(n/p)$

PVD
TCO
sputtering

Metallization
Screen
printing
and curing
 $\sim 200^\circ\text{C}$



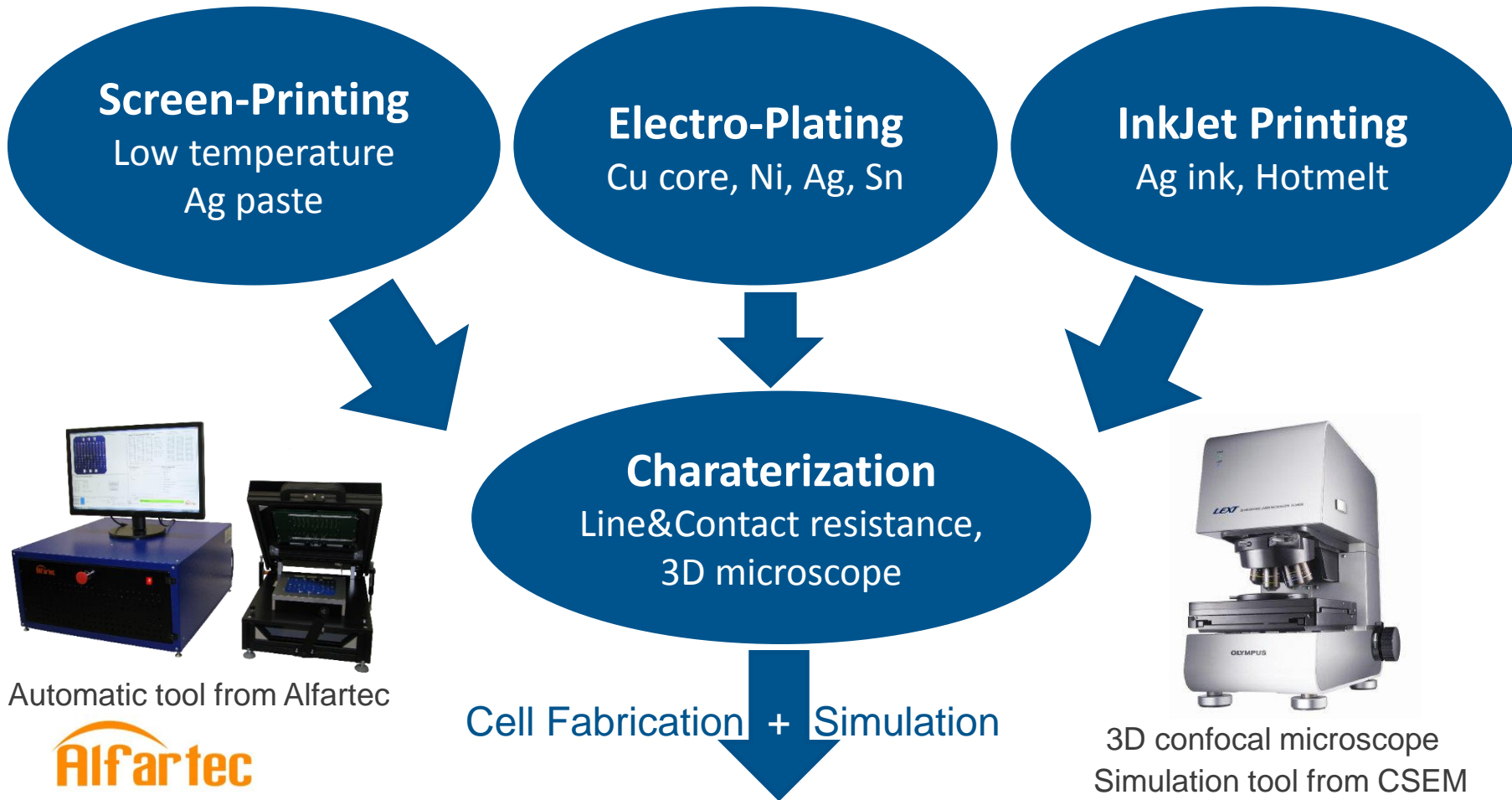
THIN FILMS Stability $< 230^\circ\text{C}$



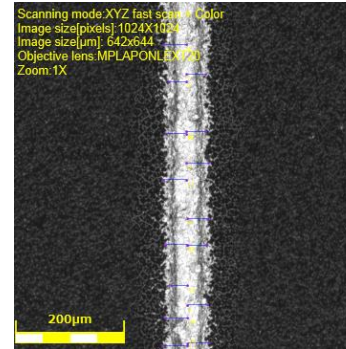
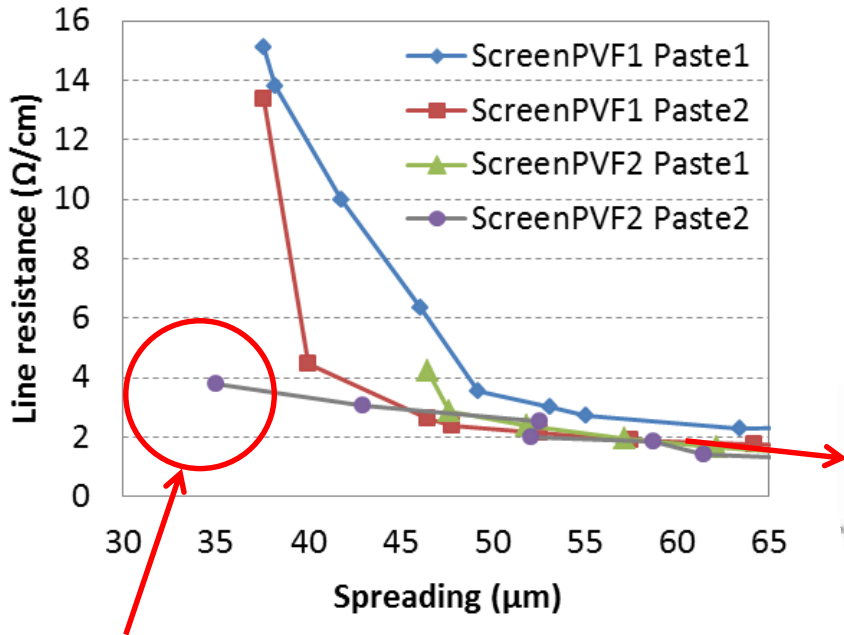
How to have high bulk conductivity with low process temperature (<230°C)?



Metallization Platform at CSEM

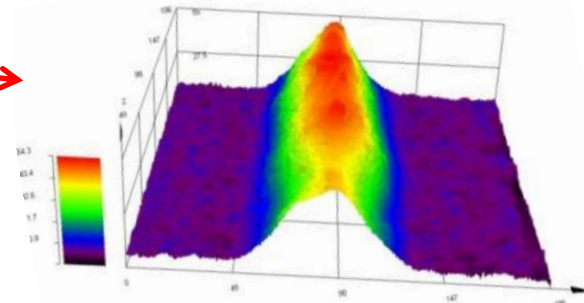


Screen-printing Optimization



Confocal images of print done with the 65 μm opening

Spreading = $80 \pm 5 \mu\text{m}$
Height = $25 \pm 2 \mu\text{m}$



Line resistance $< 0.35 \Omega/\text{cm}$

Bulk resistivity $\sim 5 - 7 \mu\Omega.\text{cm}$

210°C 30min



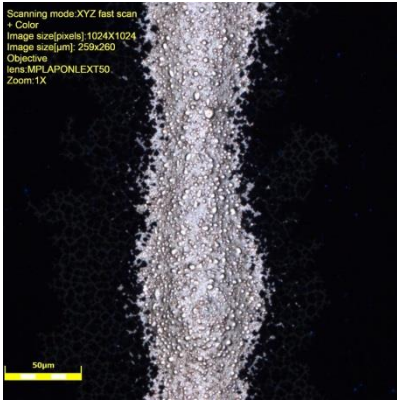
Confocal images of print done with the 20 μm opening

Spreading = $34 \pm 4 \mu\text{m}$
Height = $6 \pm 2 \mu\text{m}$

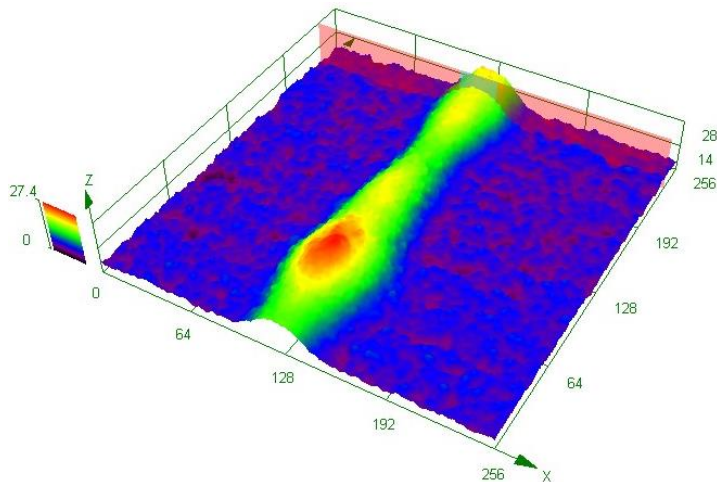
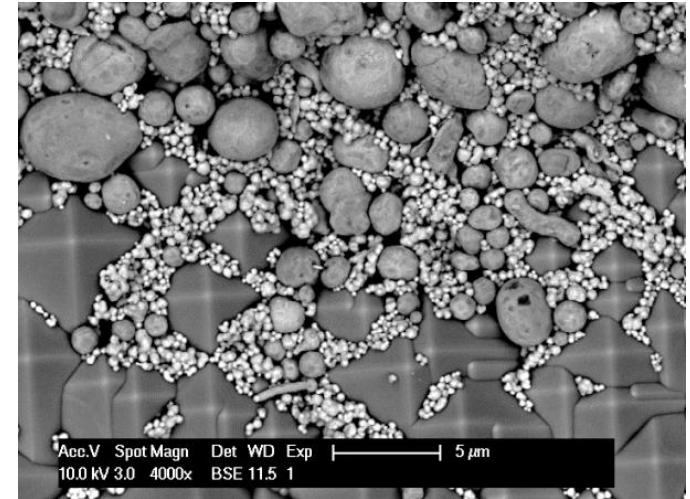
Line resistance $< 4 \Omega/\text{cm}$

Copper paste

Paste and Print results



- Copper-based paste for Screen-printing from NAMICS Corp.
- Finger spreading = 59 μm
Finger height = 14.5 μm
- Finger line resistance = 4.5 Ω/cm



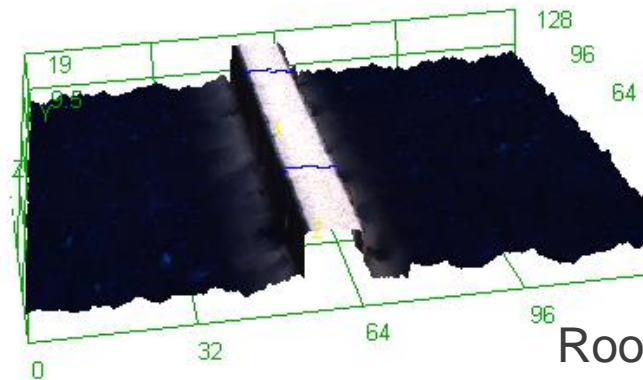
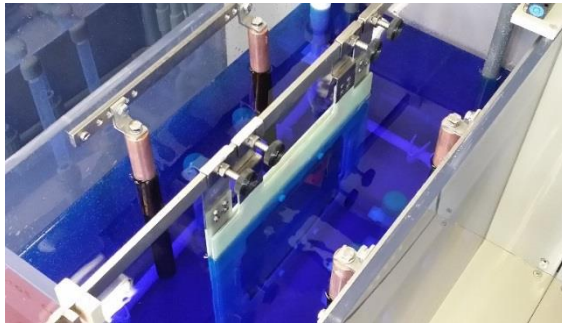
Bulk resistivity ~ 23 $\mu\Omega.\text{cm}$

210°C 30min in N₂

Copper plating: equipment + process

Pilot-demo vertical line

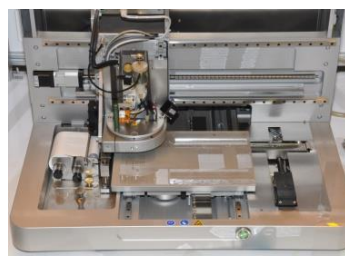
- Direct plating, Light induced plating, plating on seed
- Bifacial plating
- Ni, Cu, Sn, Ag plating solution



Width[μm]	Height[μm]
15.6	9.8

Room Temperature, wet process

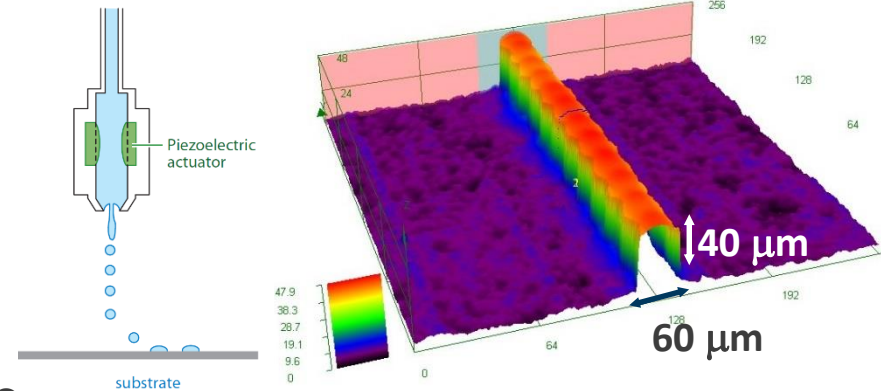
Bulk resistivity ~ 1.8 - 2 $\mu\Omega\text{.cm}$



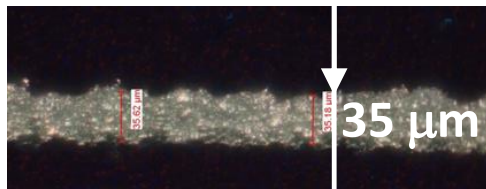
Ag Ink-jet printing

Direct metallization

- Printing strategies **optimization**
- **35 μm width finger** (thin deposit)
- 60 μm width finger with aspect **ratio of 0.7**
- Resistivity:
 - 320 $\mu\Omega\cdot\text{cm}$ after 20 min at 100°C
 - 6 $\mu\Omega\cdot\text{cm}$ after 60 min at 200°C
- Cost of **nano-ink** is relatively high

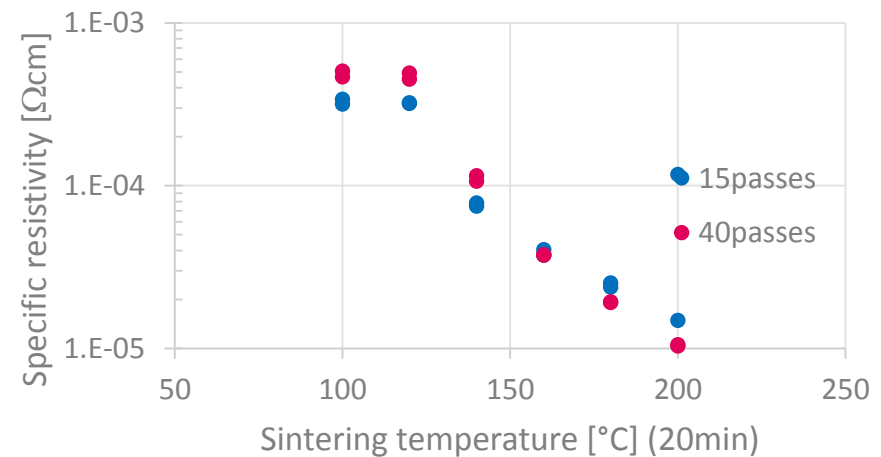


Width[μm]	Height[μm]	CS area[μm^2]
60.4	40.4	880

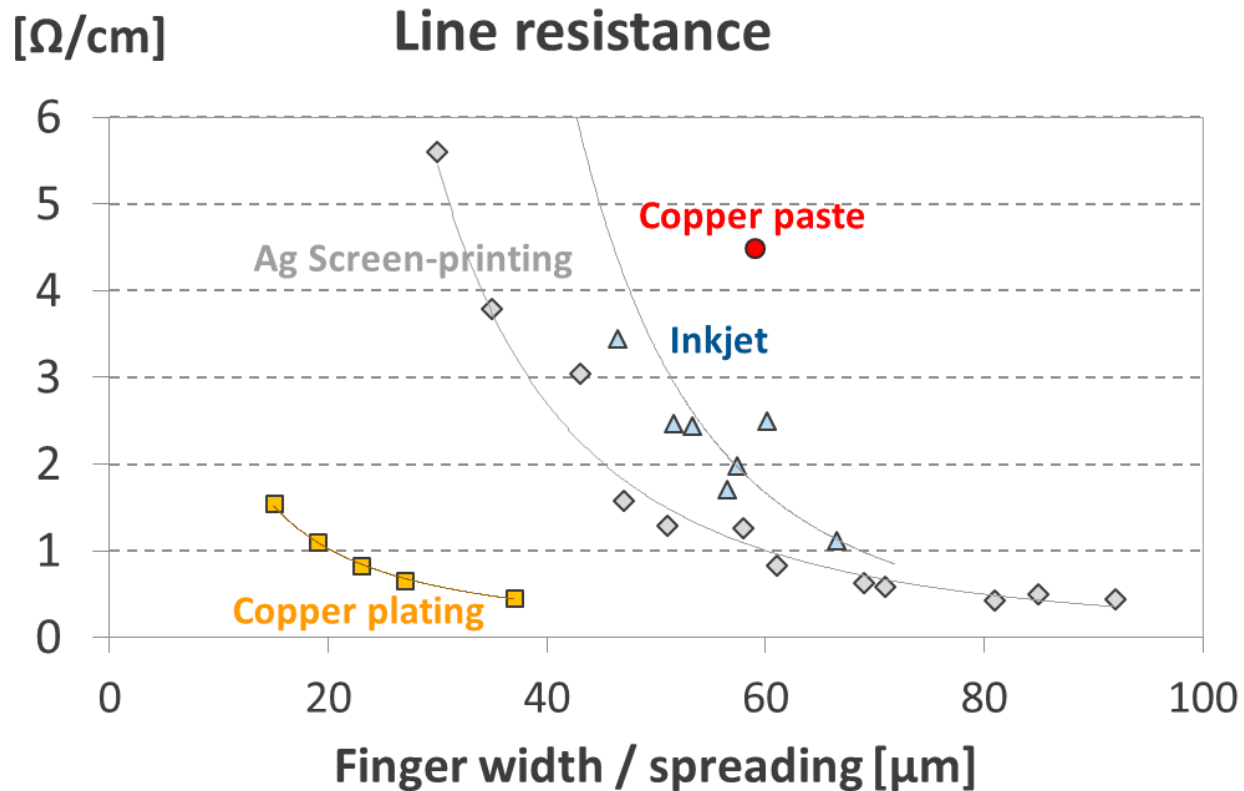


Bulk resistivity ~ 6 $\mu\Omega\cdot\text{cm}$

200°C 60 min



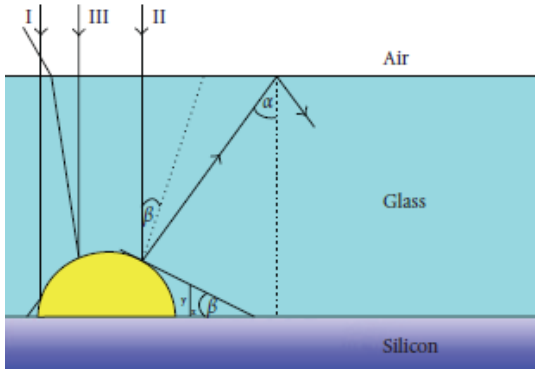
Summary Metallization for SHJ Solar Cell



- Cu plating : fine line with high conductivity
- Inkjet printing: cannot go below 1 Ω/cm

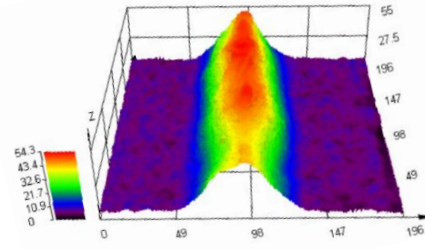
What will happen in the module?

Metallization Optical Gain

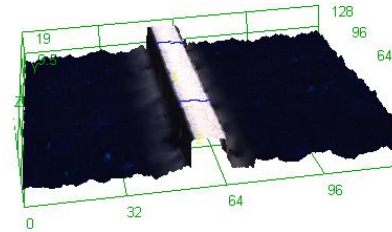


R. Woehl *et al.*,
Advances in OptoElectronics, vol. 2008 (2008)

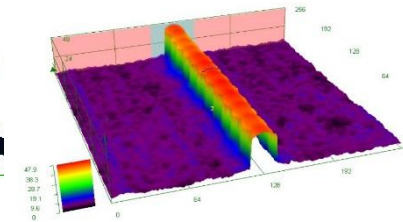
Screen-printing



Cu plating



Inkjet printing



Effective Optical Width	60%	90%	90%
	Measured + simulated	simulated	simulated

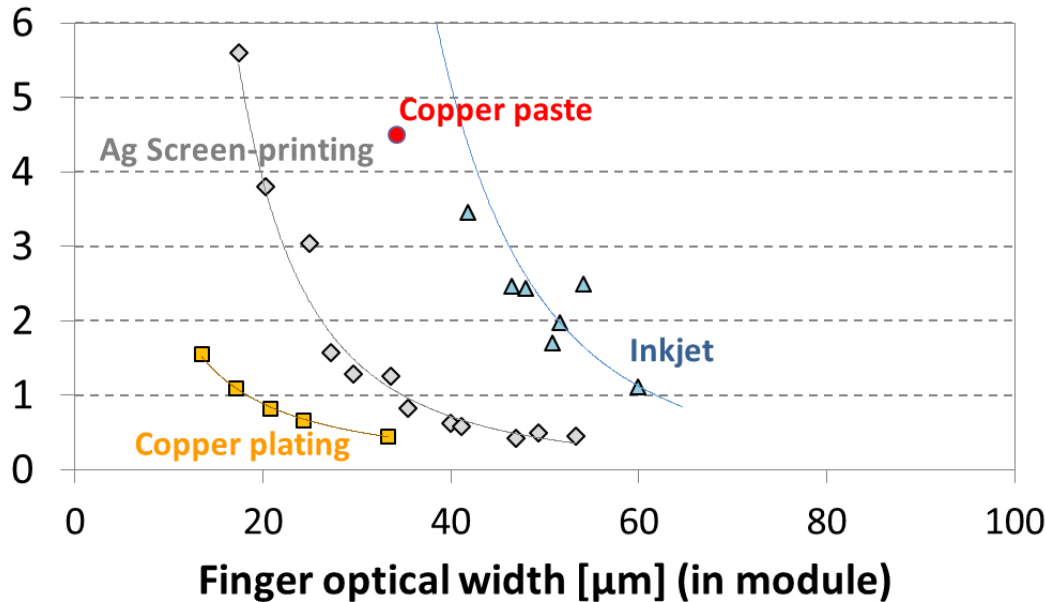
[Ω/cm]

Line resistance

Measured + simulated

simulated

simulated



In module, Screen-printing shadowing is reduced and closer to Copper Plating

Higher efficiency with SmartWire due to reduce losses

Power losses and module integration

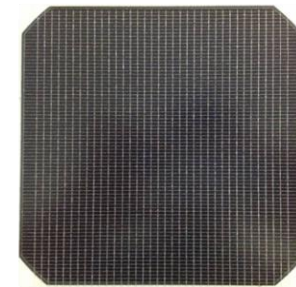
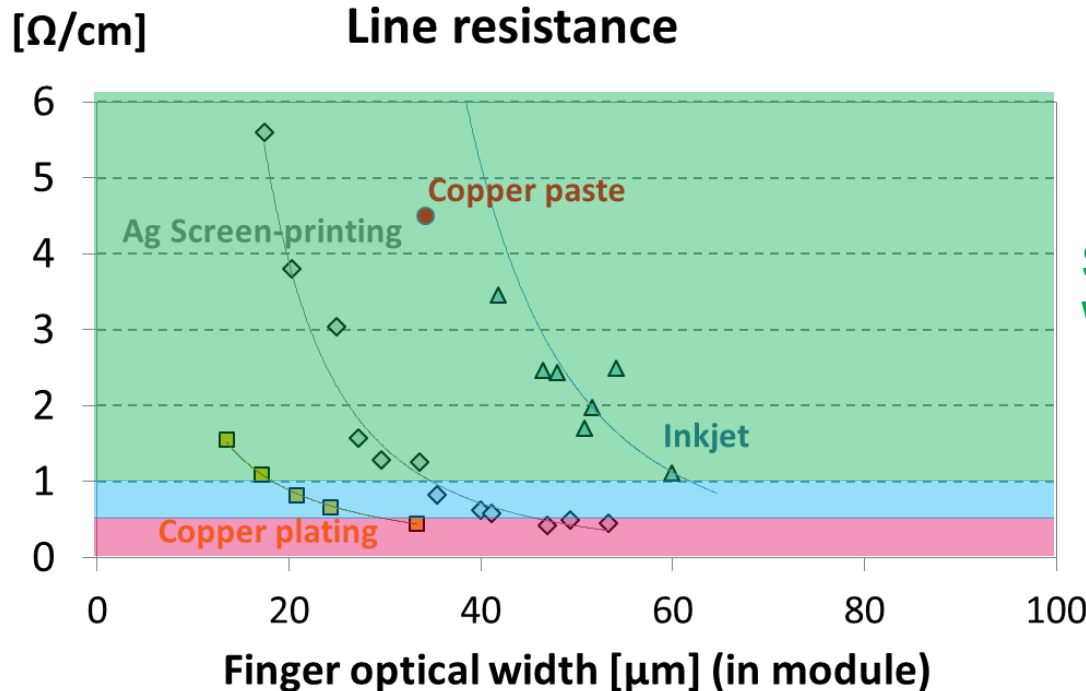
- Power dissipation losses in fingers (P_f) vs finger line resistance (R_f) and finger length (L_f) [1]

$$P_f = Const \cdot R_f L_f^2 \approx 1\%$$



For 80 fingers

$R_{f,18wires} \approx 10 \text{ } \Omega/\text{cm}$
 $R_{f,5BB} \approx 1 \text{ } \Omega/\text{cm}$
 $R_{f,3BB} \approx 0.4 \text{ } \Omega/\text{cm}$



SmartWire



Smart Wire

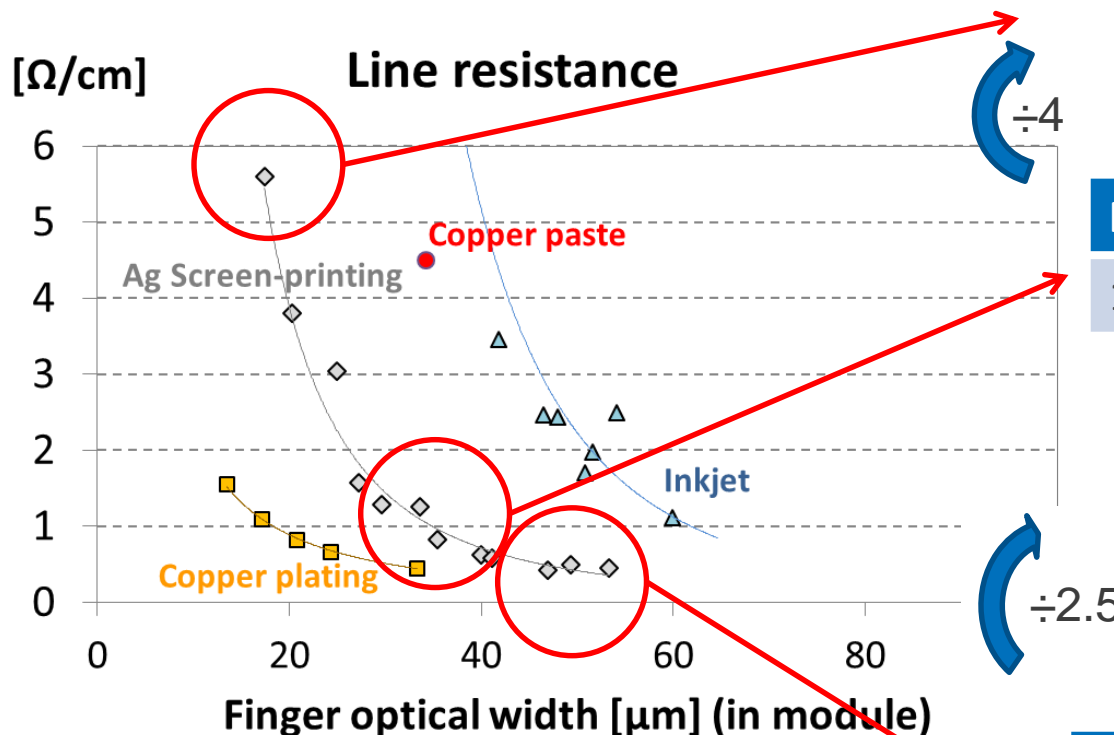
5BB

5BB
3BB

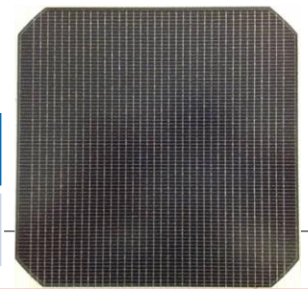


3BB

Ag deposited weight



Front	Bifacial
25 mg	55 mg



Smart Wire

Ag cost = 2.7 ct€/cell

Front	Bifacial
100 mg	220 mg



5BB

Ag cost = 11 ct€/cell

Front	Bifacial
250 mg	550 mg



3BB

Ag cost = 27 ct€/cell

Lower cost with SmartWire due to reduce silver deposition

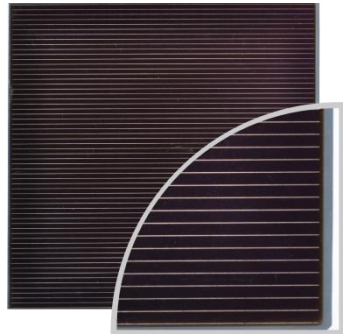
SmartWire Concept

No busbar cells

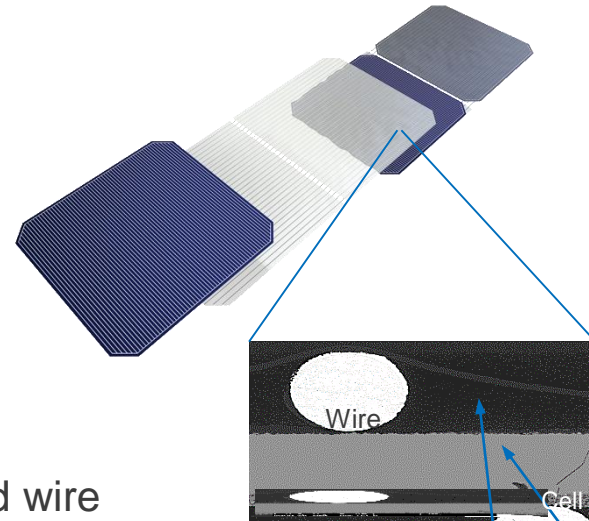
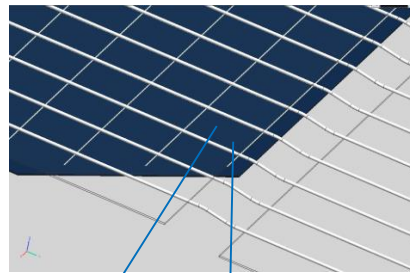
Wire interconnection

10 cells string

60 cells module

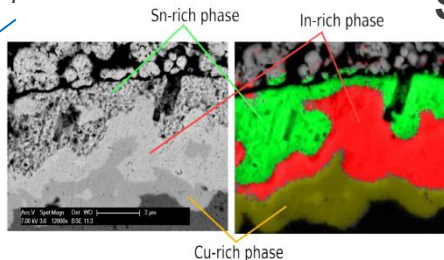
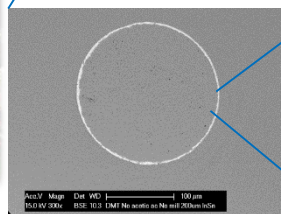


Cell measurement
GridTouch® from
PASAN



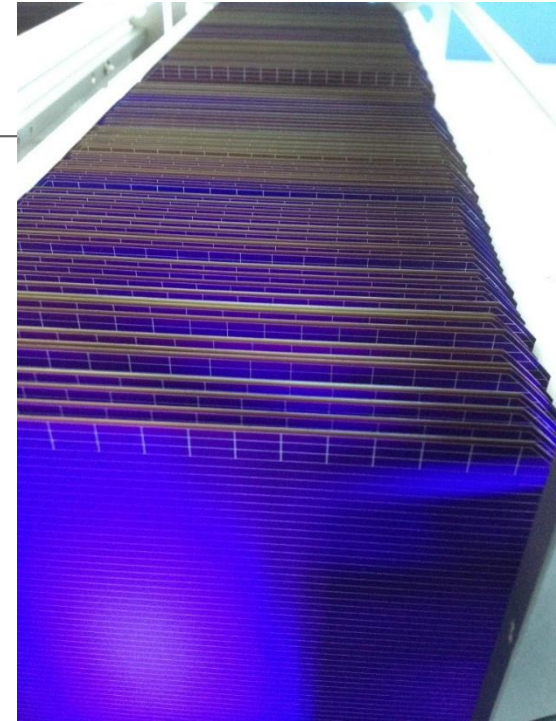
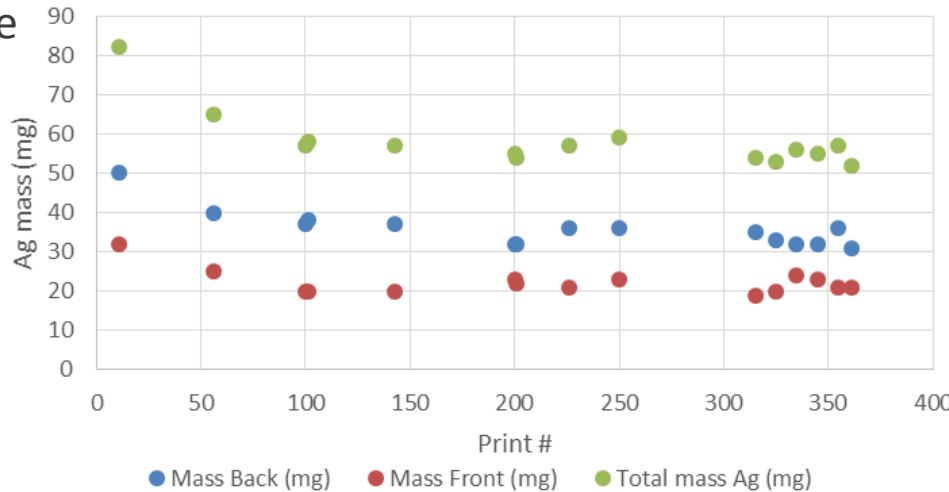
InSn Coated wire
 $T_F=120^\circ\text{C}$

Supporting foil + adhesive



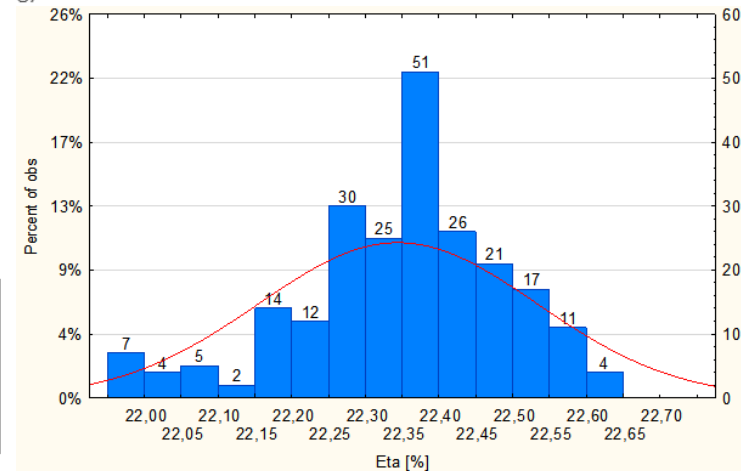
Screen-Printing in Pilot Production

- **55 mg Ag in total** for bifacial cells in pilot production line

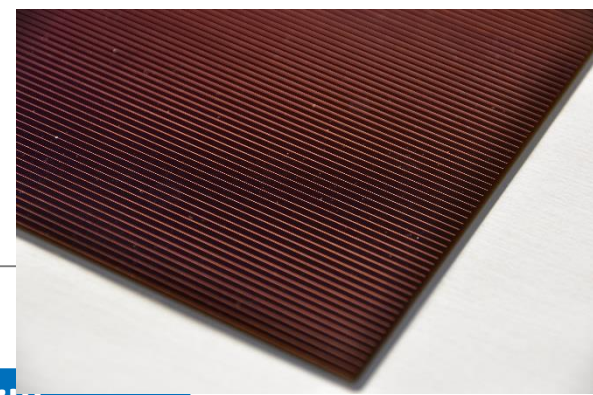


- **43 μm line width** at the back and **48 μm** line width at the front
- **Average Eff = 22.4%**

Cost of silver* for 55 mg/wafer of silver paste = 0.6 €ct/Wp (1.7 €/module)

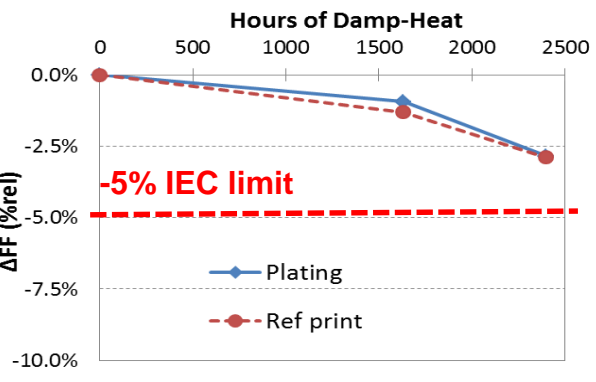
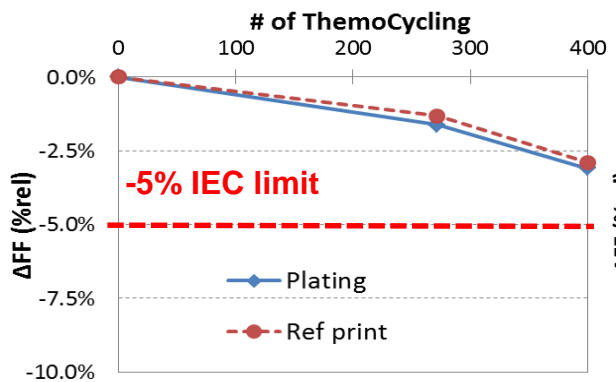
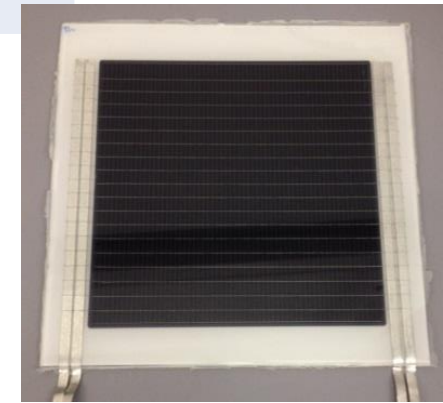


Busbar-less cells and SmartWire module



Metallization	Cell Efficiency* (%)	Module Reliability
Ag Screen-printing	22.7	4x IEC standard
Cu Screen-printing	22.4	1x IEC standard
Cu plating	22.8	2x IEC standard
Inkjet printing	22.4	1x IEC standard

**Record power module 60 cells
HJT = 330 Wp**



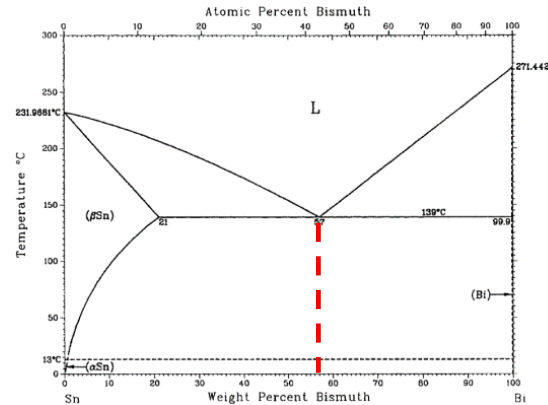
- 1x IEC standard →
- 200 Thermocycling between -40°C and +85°C
- 1000 hours in damp-heat 85°C and 85% relative humidity

How to further reduce cost?

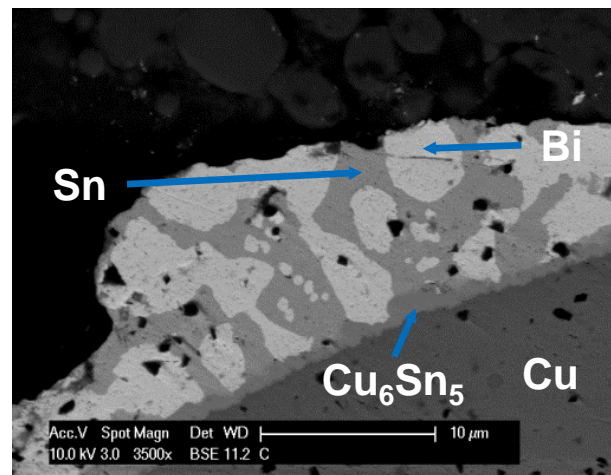
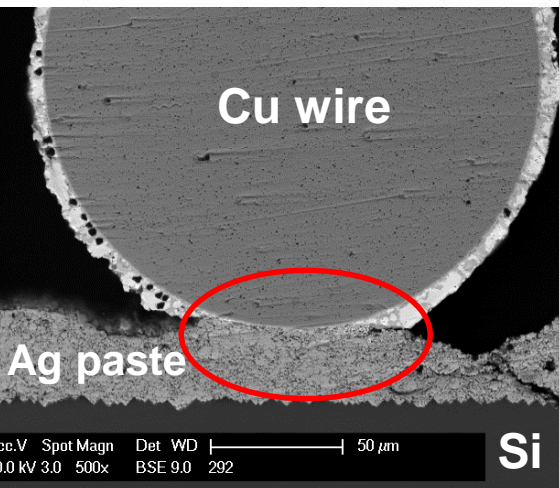
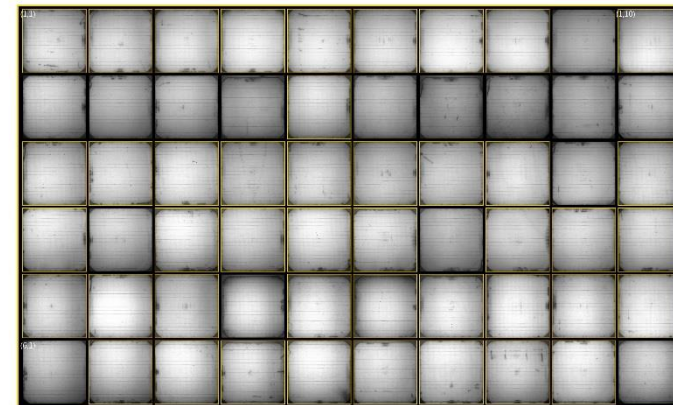
New Indium-free coating for SmartWire



- Price cheaper than InSn → only 0.25 €/ct/Wp
- BiSn-based solder
- CTE close to pure Cu
- BiSn contact to Cu:
 - Cu_3Sn
 - Cu_6Sn_5



	FF	Isc	Voc	Pmax
Module (%)	77.2	9.01	44.1	307
60 cells				



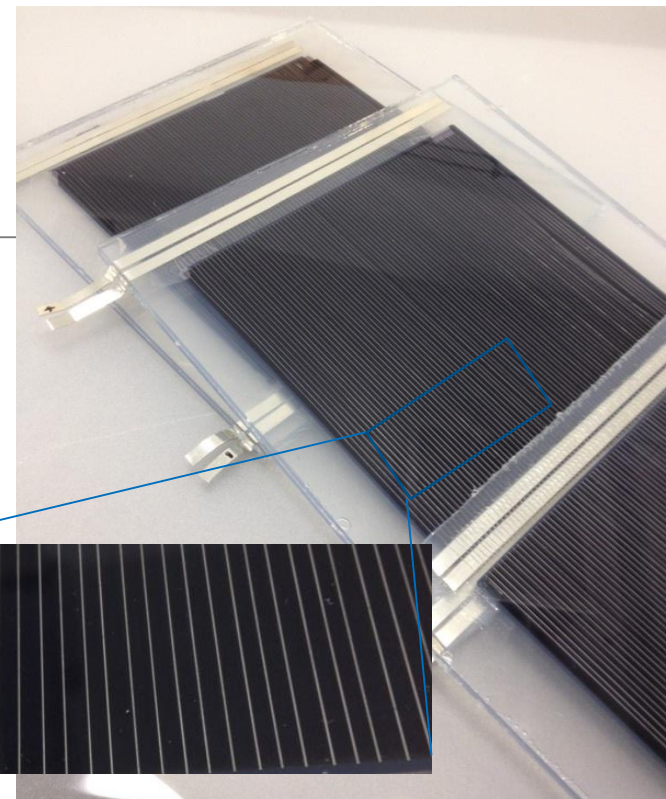
Pass 3x IEC
600TC & 3000h DH

With less than 3% degradation in power

How to remove cell metallization?

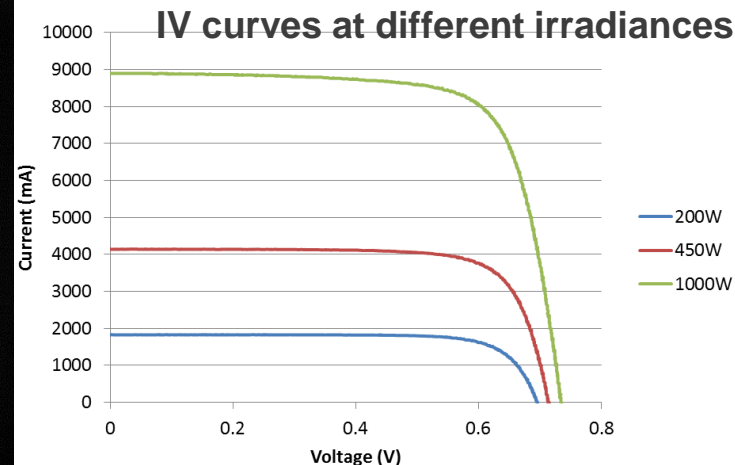
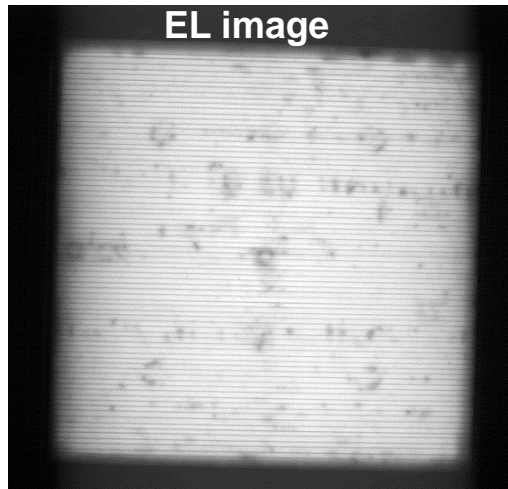
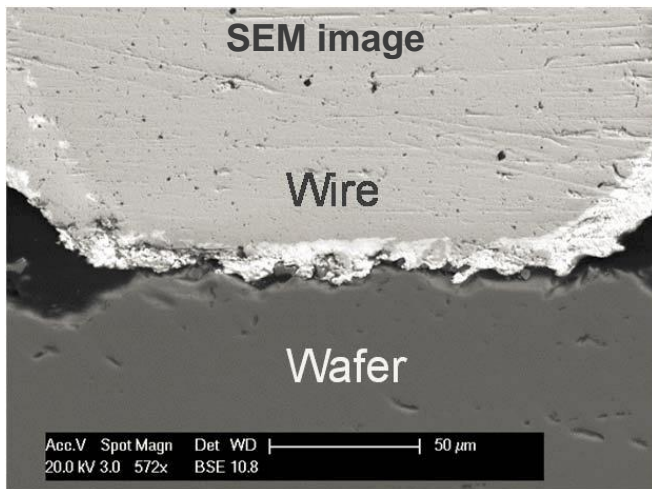
No Metallization

- Direct contact between InSn wire coating and TCO from the cell



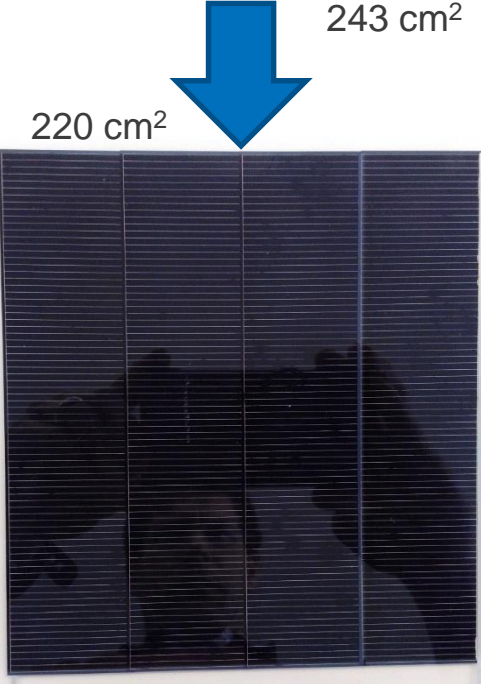
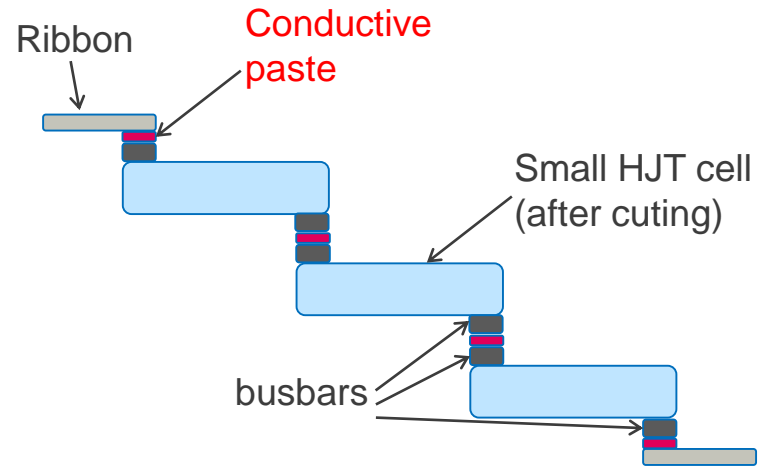
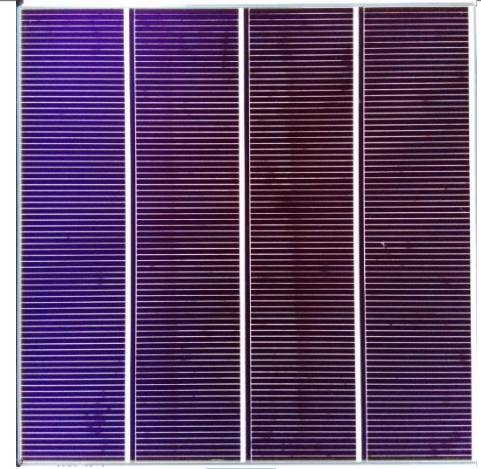
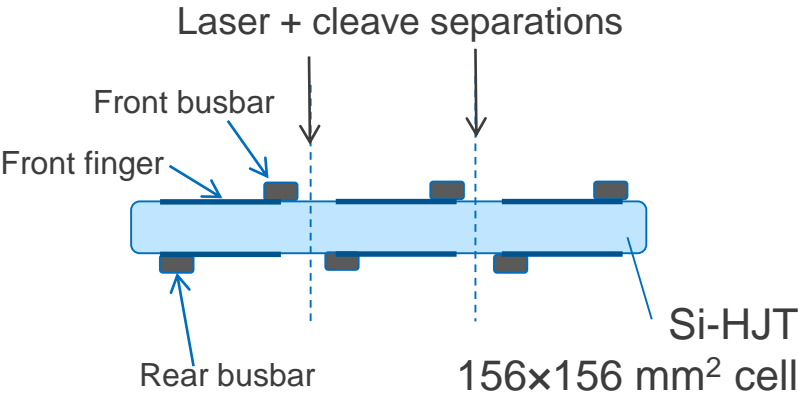
Irradiance	Voc (V)	Jsc (mA.cm ⁻²)	Module eff (%)	FF (%)
200 W/m ²	0.696	7.73	20.6	77.8
450 W/m ²	0.714	17.40	20.7	76.5
1000 W/m ²	0.734	37.30	19.9	74.0

Module without metallization at 19.9 % eff.

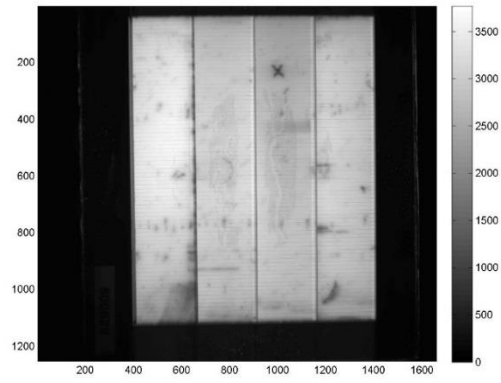


How to remove wire or ribbon interconnection?

Module with Shingle Cell Interconnection

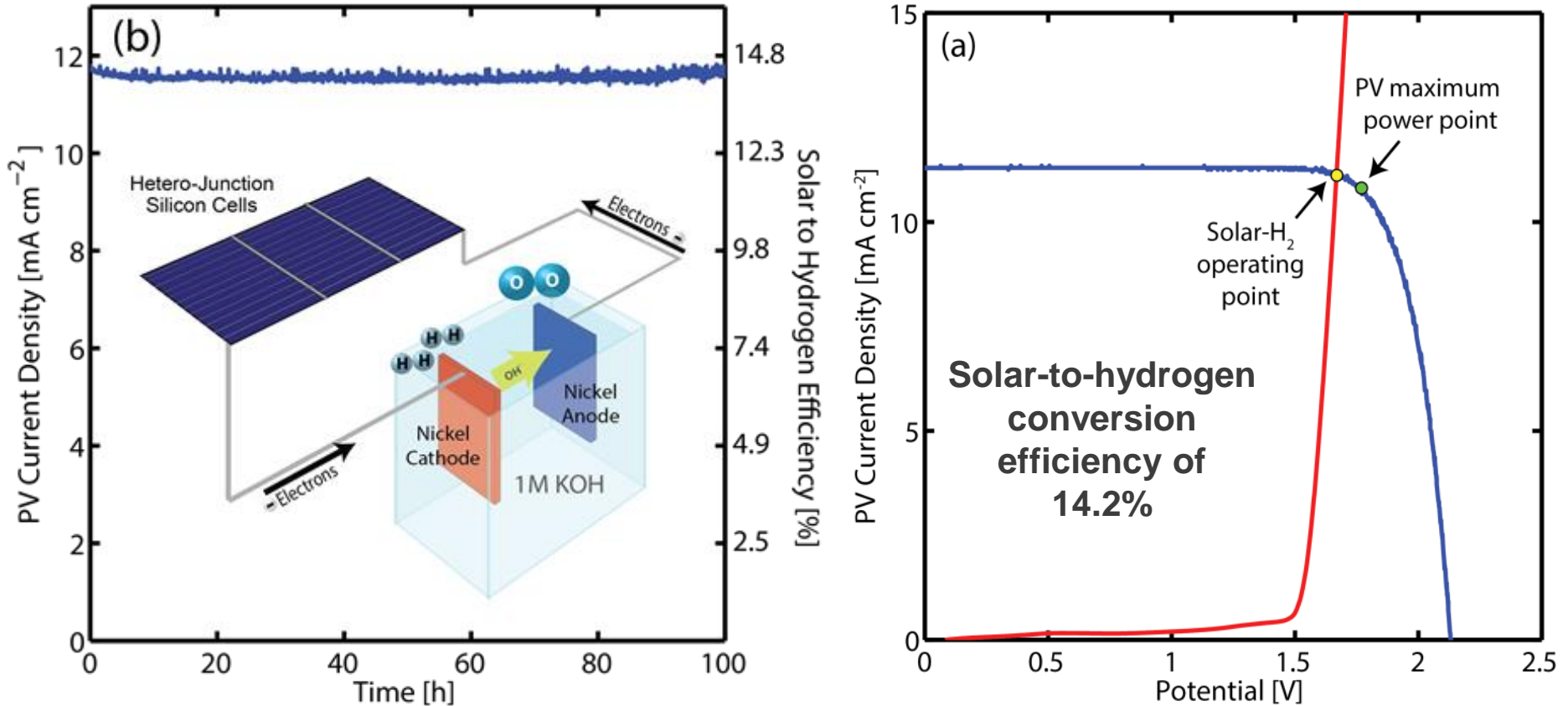


CTM losses	Eff da (%)	Power (%)
	+1.5%	-4.2%



21% module efficiency
Pass 400TC

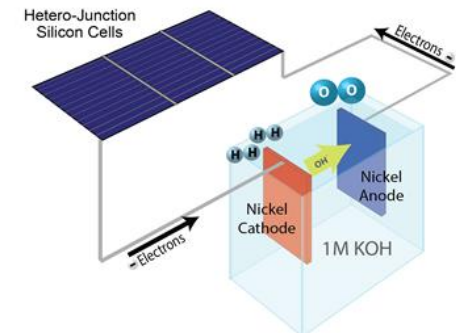
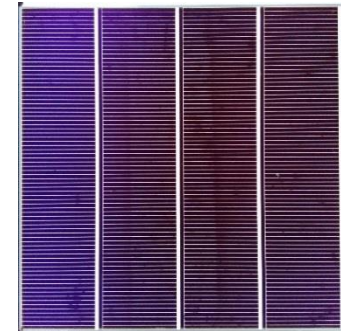
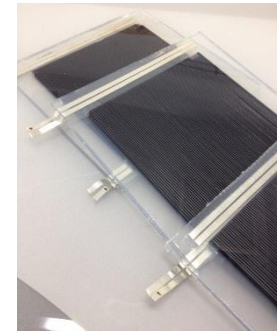
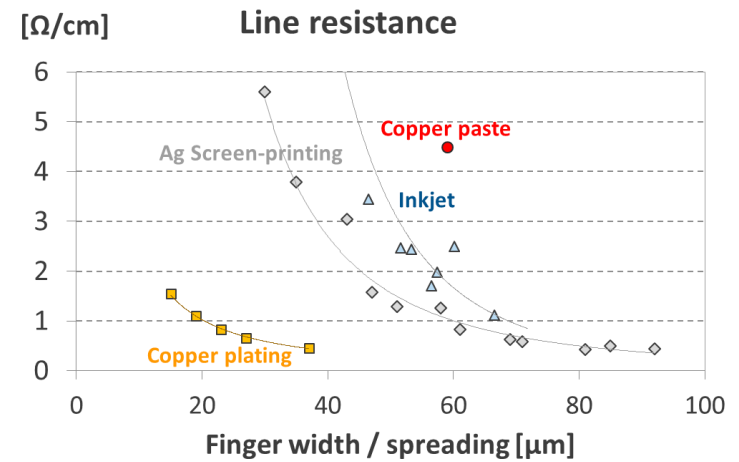
Solar Water Splitting



Highest efficiency in the world for solar water splitting based on Si PV & earth-abundant components

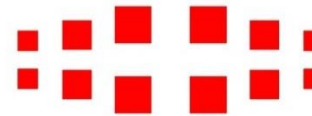
Conclusions

- **CSEM metallization platform**
 - Copper plating
 - Silver screen-printing
 - Silver inkjet printing
- **CTM gain** for metallization shadowing
- **SmartWire** reduces metallization cost and increases module efficiency
- **Indium-free SmartWire** for further cost reduction
- Module **without cell metallization**
- Module **without ribbon or wire interconnection**
- **World record** for solar water splitting based on Si PV & earth-abundant components



Acknowledgments

- European Union's Seventh Programme for research with funding of the HERCULES project
- Swiss Commission for Technology and Innovation with funding of the SmartWire and of DEFIA project
- Swiss Federal Office of Energy with funding of the Swiss Inno HJT project
- Choshu Industry Co, for cell precursors
- PVF-Vertriebs for the screen manufacturing and funding
- All co-authors for the work



SWISS INNO HJT



Schweizerische Eidgenossenschaft
Confédération suisse
Confederazione Svizzera
Confederaziun svizra

Swiss Federal Office of Energy SFOE



Schweizerische Eidgenossenschaft
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Swiss Confederation

Commission for Technology and Innovation CTI



MEYER BURGER



Precision mesh & solutions
for industrial applications



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Thank you for your attention

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